

Amendments to the Specification:

All amendments are shown with deleted text struckthrough or double bracketed and new text underlined.

Please insert the following as a new section prior to the Background of the Invention.

CROSS-REFERENCE TO RELATED APPLICATIONS

This application claims priority to and benefit of Republic of China (Taiwan) Application No. 092102129, filed on January 30, 2003, entitled: METHOD FOR IMPROVING THE DEPTH OF FIELD AND RESOLUTION OF MICROSCOPY, by inventor Ann-Shyn Chiang.